SANYO

1M(65536words×16bits) Flash EEPROM

Features

CMOS Flash EEPROM Technology
Single 5-Volt Read and Write Operations
Sector Erase Capability: 128word per sector
Fast Access Time: 40ns/45ns/55ns/70ns
Low Power Consumption
Active Current (Read): 50 mA (Max.)
Standby Current: 100 μA (Max.)
High Read/Write Reliability
Sector-write Endurance Cycles: 10^4
10 Years Data Retention
Latched Address and Data
Self-timed Erase and Programming
Word Programming: 40μs (Max.)
End of Write Detection: Toggle Bit/ $\overline{\text{DATA}}$ Polling
Hardware/Software Data Protection
Packages Available
LE28F1101T **:** 40-pin TSOP Normal(10×14mm)

Product Description

The LE28F1101T is a 64K ×16 CMOS sector erase, word program EEPROM. The LE28F1101T is manufactured using SANYO's proprietary, high performance CMOS Flash EEPROM technology. Breakthroughs in EEPROM cell design and process architecture attain better reliability and manufacturability compared with conventional approaches. The LE28F1101T erases and programs with a 5-volt only power supply.
LE28F1101T is offered in TSOP40 (10×14mm) packages.

Featuring high performance programming, LE28F1101 typically word programs in 30μs. The LE28F1101 typically sector (128word) erases in 2ms. Both program and erase times can be optimized using interface feature such as Toggle bit or $\overline{\text{DATA}}$ Polling to indicate the completion of the write cycle. To protect against an inadvertent write, the LE28F1101T has on chip hardware and software data protection schemes. Designed, manufactured, and tested for a wide spectrum of applications, the LE28F1101T is offered with a guaranteed sector write endurance of 10^4 cycles. Data retention is rated greater than 10 years.

The LE28F1101T is best suited for applications that require reprogrammable nonvolatile mass storage of program or data memory. For all system applications, the LE28F1101T significantly improves performance and reliability, while lowering power consumption when compared with floppy diskettes or EPROM approaches. EEPROM technology makes possible convenient and economical updating of codes and control programs on-line. The LE28F1101T improves flexibility, while lowering the cost, of program and configuration storage applications.

Figure 1 shows the pin assignments for the 40 lead Plastic TSOP packages. Figure 2 shows the functional block diagram of the LE28F1101T. Pin description and operation modes can be found in Tables 1 through 3.

Device Operation

Commands are used to initiate the memory operation functions of the device. Commands are written to the device using standard microprocessor write sequences. A command is written by asserting $\overline{\text{WE}}$ low while keeping $\overline{\text{CE}}$ low. The address bus is latched on the falling edge of $\overline{\text{WE}}$, $\overline{\text{CE}}$, whichever occurs last. The data bus is latched on the rising edge of $\overline{\text{WE}}$, $\overline{\text{CE}}$, whichever occurs first. However, during the software write protection sequence the addresses are latched on the rising edge of $\overline{\text{OE}}$ or $\overline{\text{CE}}$, whichever occurs first.

*This product incorporate technology licensed from Silicon Storage Technology, Inc.
This preliminary specification is subject to change without notice.

LE28F1101T
40-pin TSOP
(Normal)

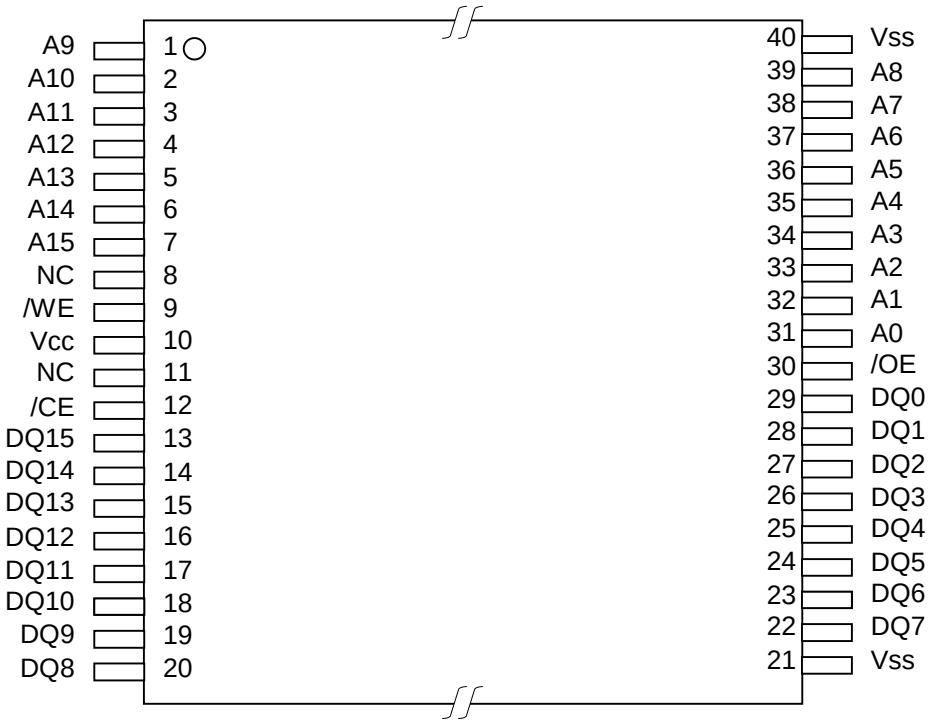


Figure 1: Pin Assignments for 40-pin Plastic TSOP

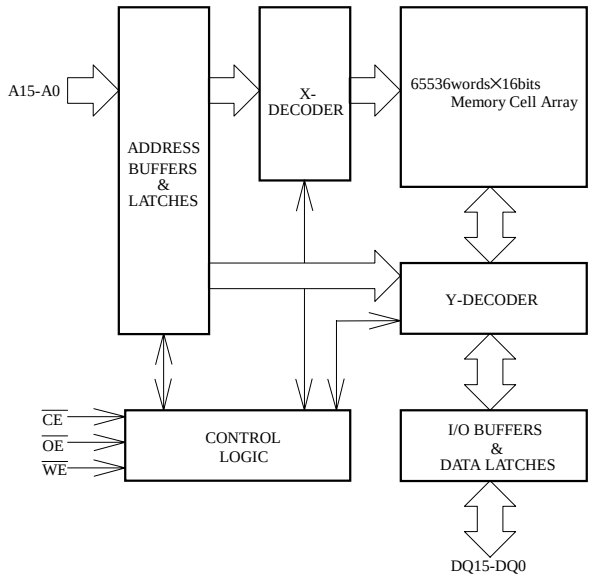


Figure 2: Functional Block Diagram of LE28F1101T

Table 1: Pin Description

Symbol	Pin Name	Functions
A15-A0	Address Inputs	To provide memory address. Addresses are internally latched during write cycle.
DQ15-DQ0	Data Input/Output	To output data during read cycle and receive input data during write cycles. Data is internally latched during a write cycle. The outputs are in tri-state when $\overline{OE}$ or $\overline{CE}$ is high.
$\overline{CE}$	Chip Enable	To activate the device when $\overline{CE}$ is low. Deselects and puts the device to standby when $\overline{CE}$ is high.
$\overline{OE}$	Output Enable	To activate the data output buffers. $\overline{OE}$ is active low.
$\overline{WE}$	Write Enable	To activate the write operation. $\overline{WE}$ is active low.
V_{CC}	Power Supply	To provide 5V±10% supply.
V_{SS}	Ground	
NC	No Connection	Unconnected Pins

Table 2: Operation Modes Selection

Mode	$\overline{CE}$	$\overline{OE}$	$\overline{WE}$	DQ	Address
Read	V_{IL}	V_{IL}	V_{IH}	D_{OUT}	A_{IN}
Write	V_{IL}	V_{IH}	V_{IL}	D_{IN}	A_{IN}
Standby	V_{IH}	X	X	High-Z	X
Write Inhibit	X	V_{IL}	X	High-Z / D_{OUT}	X
	X	X	V_{IH}	High-Z / D_{OUT}	X
Product ID	V_{IL}	V_{IL}	V_{IH}	Manufacturer Code (62H)	A15-A1=V_{IL}, A9=12V, A0=V_{IL}
				Device Code (0017H)	A15-A1=V_{IL}, A9=12V, A0=V_{IH}

Table 3: Command Summary

Command	Required Cycle	Setup Command Cycle			Execute Command Cycle		
		Operation	Address	Data	Operation	Address	Data
Sector_Erase	2	Write	X	XX20H	Write	SA	XXD0H
Word_Program	2	Write	X	XX10H	Write	PA	PD
Reset	1	Write	X	FFFFH			
Read_ID	2	Write	X	XX90H	Read	(7)	(7)
Software_Data_Unprotect (6)	7						
Software_Data_Protect (6)	7						

Definitions for Table 3:

1.Type definitions: X=high or low

2.Address definitions: SA=Sector Address=A15-A7; sector size=128word; A6-A0=X for this command

3.Address definitions: PA=Program Address=A15-A0

4.Data definition: PD=Program Data, H=number in hex.

5.SDP=Software Data Protect mode using 7-Read-Cycle-Sequence.

6. Refer to Figure 11 and 12 for the 7-Read-Cycle-Sequence Software Data Protection.

7.Address 0000H retrieves the manufacturer code of 62(Hex), address 0001H retrieves the device code of 0017(Hex).

Command Definition

Table 3 contains a command list and a brief summary of the commands.

The following is a detailed description of the options initiated by each command.

The LE28F1101T has to have the Software Data Unprotect Sequence executed prior a Word Program or Erase in order to perform those functions.

Sector_Erase Operation

The Sector_Erase operation is initiated by a setup command and an execute command. The setup command stages the device for electrical erasing of all words within a sector. A sector contains 128 words. This sector erasability enhances the flexibility and usefulness of the LE28F1101T, since most applications only need to change a small number of words or sectors, not the entire chip. The setup command is performed by a writing (20H) to the device. To execute the sector-erase operation, the execute command (D0H) must be written to the device. The erase operation begins with the rising edge of the $\overline{WE}$ pulse and terminated automatically by using an internal timer. See Figure 8 for timing waveforms.

The two-step sequence of a setup command followed by execute command ensures that only memory contents within the addressed sector are erased and other sectors are not inadvertently erased.

Sector_Erase Flowchart Description

Fast and Reliable erasing of the memory contents within a sector is accomplished by following the sector erase flowchart as shown in Figure 3. The entire procedure consists of the execution of two commands. The Sector_Erase operation will terminate after a maximum of 4ms. A Reset command can be executed to terminate the erase operation; however, if the erase operation is terminated prior to the 4ms time-out, the sector may not be completely erased. An erase command can be reissued as many times as necessary to complete the erase operation. The LE28F1101T cannot be overerased.

Word_Program Operation

The Word_Program operation is initiated by writing the setup command (10H).

Once the program setup is performed, programming is executed by the next $\overline{WE}$ pulse. See Figure 6 and 7 for timing waveforms. The address bus is latched on the falling edge of $\overline{WE}$, $\overline{CE}$, or the rising edge of $\overline{OE}$, whichever occurs first. The programming operation begins with either the rising edge of $\overline{WE}$, $\overline{CE}$, whichever occurs first. The programming operation is terminated automatically by an internal timer. See the programming characteristics and waveforms for details, Figures 4, 6 and 7.

The two-step sequence of a setup command followed by execute command ensures that only the addressed word is programmed and other words are not inadvertently programmed.

The Word_Program Flow Chart Description

Programming data into the device is accomplished by following the Word_Program flowchart as shown in Figure 3. The Word_Program command sets up the word for programming. The address bus is latched on the falling edge of $\overline{WE}$, $\overline{CE}$, whichever occurs last. The data bus is latched on the rising edge of $\overline{WE}$, $\overline{CE}$, whichever occurs first, and begins the program operation. The end of write can be detected using either the $\overline{DATA}$ polling or Toggle bit.

Reset Operation

A Reset Command is provided as a means to safely abort the erase or program command sequences. Following either setup command (erase or program) with a write of (FFFFH) will safely abort the operation. Memory contents will not be altered. After the Reset command, the device returns to the read mode. The reset command dose not enable write protect. See figure 10 for timing waveforms.

Read Operation

The read operation is initiated by setting $\overline{CE}$, $\overline{OE}$ and $\overline{WE}$ into the read mode. See Figure 5 for read memory timing waveforms and Table 2 for the read mode. Read cycles from the host retrieve data from the array. The device remains enabled for read until another operating mode is accessed.

During initial power-up, the device is in the read mode and is write protected. The device must be unprotected in order to execute a write operation

The read operation is controlled by $\overline{OE}$ and $\overline{CE}$ at logic low. When $\overline{CE}$ is high, the chip is deselected and only standby power will be consumed. $\overline{OE}$ is the output control and is used to gate to the output pins. The data bus is in a high impedance state when either $\overline{CE}$ or $\overline{OE}$ is high.

Read_ID Operation

The Read_ID operation is initiated by writing a single command (90H). A read of address 0000H will output the manufacturer's code (62H). A read of address 0001H will outputs the device code (0017H). Any other valid command will terminate this operation.

Data Protection from Inadvertent Writes

In order to protect the integrity of nonvolatile data storage, the LE28F1101T provides hardware and software features to prevent writes to the device, for example, during system power-up or power-down. Such provisions are described below.

Hardware Write Protection

The LE28F1101T is designed with hardware features to prevent inadvertent writes. This is done in the following ways:

1. Write Inhibits Mode: $\overline{OE}$ low, $\overline{CE}$ high or $\overline{WE}$ high inhibit the write operation.
2. Noise and Glitch Protection: Write operations are initiated when the $\overline{WE}$ pulse width is less than 15 ns.
3. After power-up the device is in the read mode and the device is in the write protect state.

Software Data Protection

Provisions have been made to further prevent inadvertent writes through software. In order to perform the write functions of erase or program, a two-step command sequence consisting of a setup command followed by an execute command avoids inadvertent erasing or programming of the device.

The LE28F1101T will default to write protect after power-up. A sequence of seven consecutive reads at specified device addresses will unprotect the device. The address sequence is 1823H, 1820H, 1822H, 0418H, 041BH, 0419H, 041AH. The address has to be latched in the rising edge of $\overline{OE}$ or $\overline{CE}$, whichever occurs first. A similar 7-read-sequence of 1823H, 1820H, 1822H, 0418H, 041BH, 0419H, 040AH will protect the device. Also, refer to Figure 11, 12 for the 7-read-sequence Software Write Protection. The DQ pins can be in any state (i.e., high, low, or High-Z).

End of Write Detection

Detection of when a write cycle ended is necessary to optimize system performance. The end of a write cycle (erase or program) can be detected by three means: 1) monitoring the $\overline{DATA}$ polling bit; 2) monitoring the Toggle bit; 3) by two successive reads of the same data. These three detection mechanisms are described below.

$\overline{DATA}$ Polling (DQ7)

The LE28F1101T features $\overline{DATA}$ Polling to indicate a write cycle. During a write cycle, any attempt to read the last word loaded will result in the complement of the loaded data on DQ7. Once the write cycle is completed, DQ7 will show true data. See Figure 13 for timing waveforms. In order for $\overline{DATA}$ Polling to function correctly, the word being polled must be erased prior to programming.

Toggle Bit (DQ6)

An alternate means for determining the end of a write cycle is by monitoring the Toggle Bit DQ6. During a write operation, successive attempts to read data from the device will result in DQ6 toggling between logic "1" (high) and "0" (low). Once the write cycle has completed, DQ6 will stop toggling and valid data will be read. The Toggle Bit may be monitored any time during the write cycle. See Figure 14 for timing waveforms.

Successive Reads

An alternate means for determining the end of a write cycle is by reading the same address for two consecutive data matches.

Product Identification

The Product Identification mode identifies the device and manufacturer as SANYO. This mode may be accessed by hardware or software operations. The hardware operation is typically used by an external programming to identify the correct algorithm for the SANYO LE28F1101T. Users may wish to use the software operation to identify the device (i.e., using the device code). For details, see Table 2 for the hardware operation. The manufacturer and device codes are the same for both operations.

Decoupling Capacitors

Ceramic capacitors (0.1μF) must be added between V_{CC} and V_{SS} for each device to assure stable flash memory operation.

The attention to the usage of this LSI

For the reasons of using ATD (Address Transition Detector) Circuit, the output data of this LSI directly after supplying voltage, program operation or erase operation are invalid. The valid data would be offered after the transition of at least one of $\overline{CE}$ or address signals under the stable voltage.

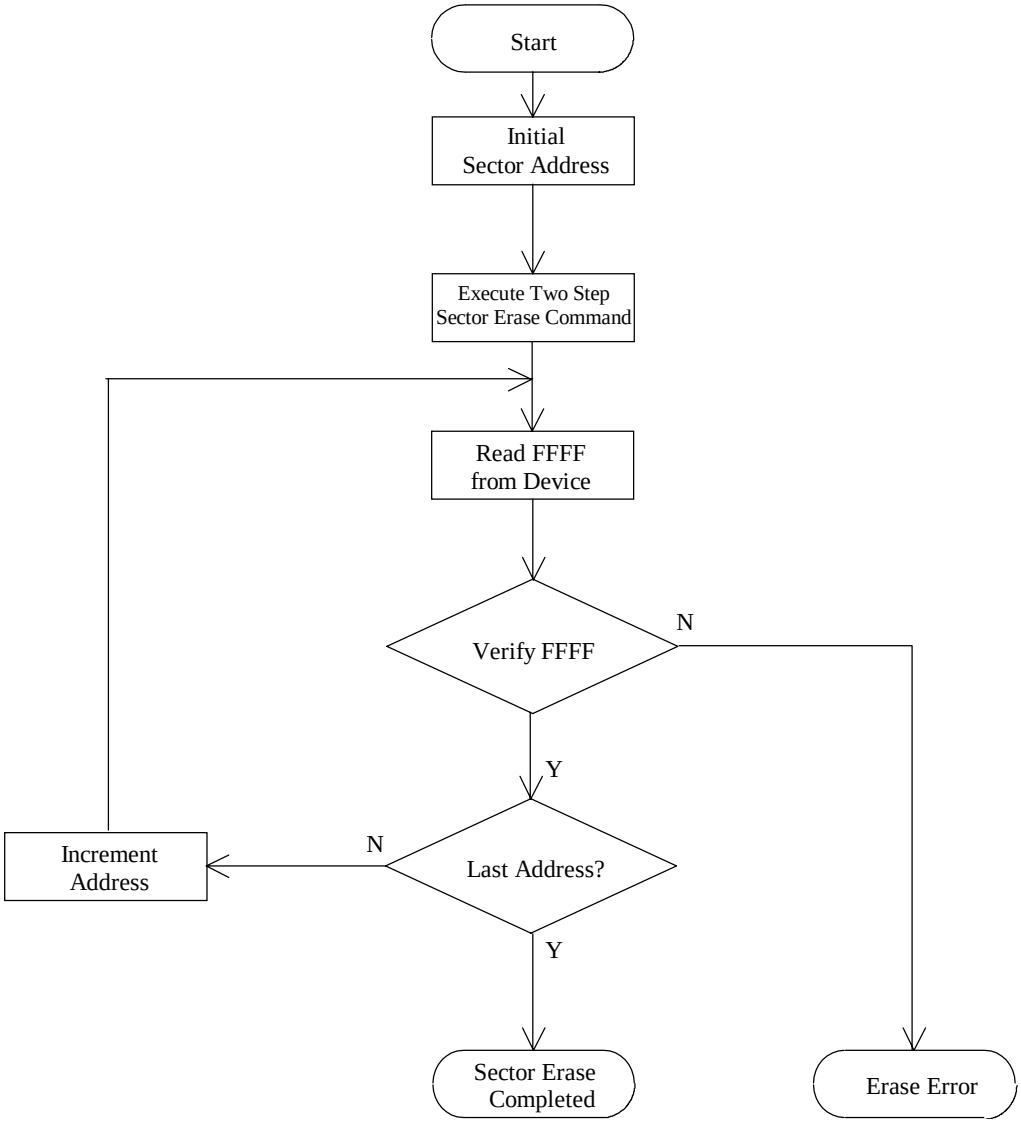


Figure 3: Sector_Erase Flowchart

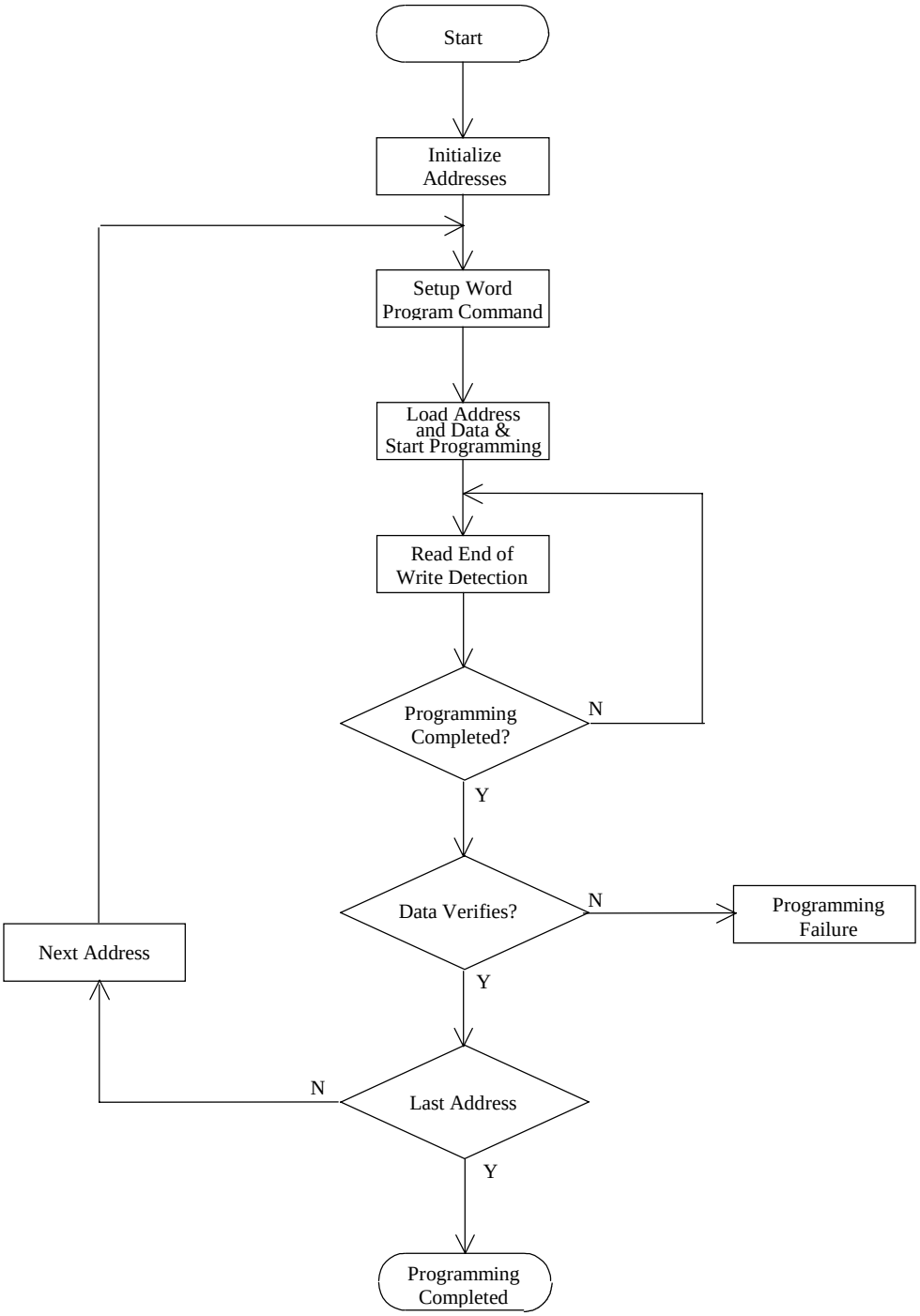


Figure 4: Word_Program Flowchart

Absolute Maximum Stress Ratings

Temperature Under Bias.....-55 ºC ~ 125 ºC
Storage Temperature.....-65 ºC ~ 150 ºC
D.C. Voltage on Any Pin to Grand Potential.....-0.5V ~ V_{CC}+0.5V
Transient Voltage (<20ns) on any Pin to Grand Potential .....-2.0V ~ V_{CC}+2.0V
Voltage on A9 to Grand Potential.....-0.5V ~ 14.0V

Operating Range

Ambient Temperature.....0 ºC ~ 70 ºC
Supply Voltage (V_{CC}) .....4.5V ~ 5.5V

DC Operating Characteristics

Symbol	Parameter	Limit			Units	Test Condition
		Min.	Typ.	Max.		
I_{CCR}	Power Supply Current (Read)			50	mA	$\overline{CE}$ = $\overline{OE}$ =V_{IL}, $\overline{WE}$ =V_{IH}, all DQs open Address inputs=V_{IH} / V_{IL}, at f=1/tRC, V_{CC}=V_{CC} max.
I_{CCW}	Power Supply Current (Write)			70	mA	$\overline{CE}$ = $\overline{WE}$ =V_{IL}, $\overline{OE}$ =V_{IH}, V_{CC}=V_{CC} max.
I_{SB1}	Standby V_{CC} Current (TTL input)			3	mA	$\overline{CE}$ =V_{IH}, V_{CC}=V_{CC} max.
I_{SB2}	Standby V_{CC} Current (CMOS input)			100	µA	$\overline{CE}$ =V_{CC}-0.3V, V_{CC}=V_{CC} max.
I_{LI}	Input Leakage Current			10	µA	V_{IN}=V_{SS}~V_{CC}, V_{CC}=V_{CC} max.
I_{LO}	Output Leakage Current			10	µA	V_{IN}=V_{SS}~V_{CC}, V_{CC}=V_{CC} max.
V_{IL}	Input Low Voltage			0.8	V	V_{CC}=V_{CC} max.
V_{IH}	Input High Voltage	2.2			V	V_{CC}=V_{CC} min.
V_{OL}	Output Low Voltage			0.8	V	I_{OL}=1.6mA, V_{CC}=V_{CC} min.
V_{OH}	Output High Voltage	2.4			V	I_{OH}= -100µA, V_{CC}=V_{CC} min.

Power-up Timing

Symbol	Parameter	Maximum	Units
tPU_READ	Power-up to Read Operation	10	ms
tPU_WRITE	Power-up to Write Operation	10	ms

Capacitance (Ta=25ºC, f=1MHz)

Symbol	Descriptions	Maximum	Units	Test Condition
C_{DQ}	DQ Pin Capacitance	12	pF	V_{DQ} = 0V
C_{IN}	Input Capacitance	6	pF	V_{IN} = 0V

AC Characteristics

Read Cycle Timing Parameters

Symbol	Parameter	-40		-45		-55		-70		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
tRC	Read Cycle Time	40		45		55		70		ns
tCE	Chip Enable Access Time		40		45		55		70	ns
tAA	Address Access Time		40		45		55		70	ns
tOE	Output Enable Access Time		25		30		35		40	ns
tCLZ[(1)]	$\overline{CE}$ Low to Active Output	0		0		0		0		ns
tOLZ[(1)]	$\overline{OE}$ Low to Active Output	0		0		0		0		ns
tCHZ[(1)]	$\overline{CE}$ High to High-Z Output		20		20		25		30	ns
tOHZ[(1)]	$\overline{OE}$ High to High-Z Output		20		20		25		30	ns
tOH	Output Hold Time	0		0		0		0		ns

Erase/Program Cycle Timing Parameters

Symbol	Parameter	-40		-45		-55		-70		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
tSE	Sector Erase Cycle Time		4		4		4		4	ms
tBP	Word Program Cycle Time		40		40		40		40	µs
tAS	Address Setup Time	0		0		0		0		ns
tAH	Address Hold Time	50		50		50		50		ns
tCS	Chip Enable Setup Time	0		0		0		0		ns
tCH	Chip Enable Hold Time	0		0		0		0		ns
tOES	Output Enable Setup Time from $\overline{WE}$	20		20		20		20		ns
tOEH	Output Enable Hold Time from $\overline{WE}$	20		20		20		20		ns
tCP	Write Pulse Width ($\overline{CE}$)	100		100		100		100		ns
tWP	Write Pulse Width	100		100		100		100		ns
tCPH	$\overline{CE}$ High Pulse Width	50		50		50		50		ns
tWPH	$\overline{WE}$ High Pulse Width	50		50		50		50		ns
tDS	Data Setup Time	50		50		50		50		ns
tDH	Data Hold Time	10		10		10		10		ns
tRST	Reset Command Recovery Time		4		4		4		4	µs
tPCP	Protect Chip Enable Pulse Width	100		100		100		100		ns
tPCH	Protect Chip Enable High Time	100		100		100		100		ns
tPAS	Protect Address Setup Time	0		0		0		0		ns
tPAH	Protect Address Hold Time	50		50		50		50		ns

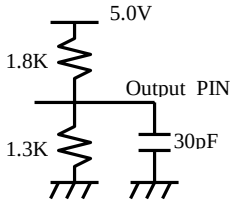
Note: [(1)]This parameter is measured only for initial qualification and after a design or process change that could affect this parameter.

AC Test Conditions

Input Pulse Levels .....0V to 3V
Input Rise/Fall Time.....5ns
Input and Output timing Reference Levels 1.5V

Output Test Load

LE28F1101T-40



LE28F1101T-45/55/70

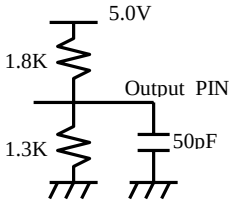


Figure 5: Read Cycle Diagram

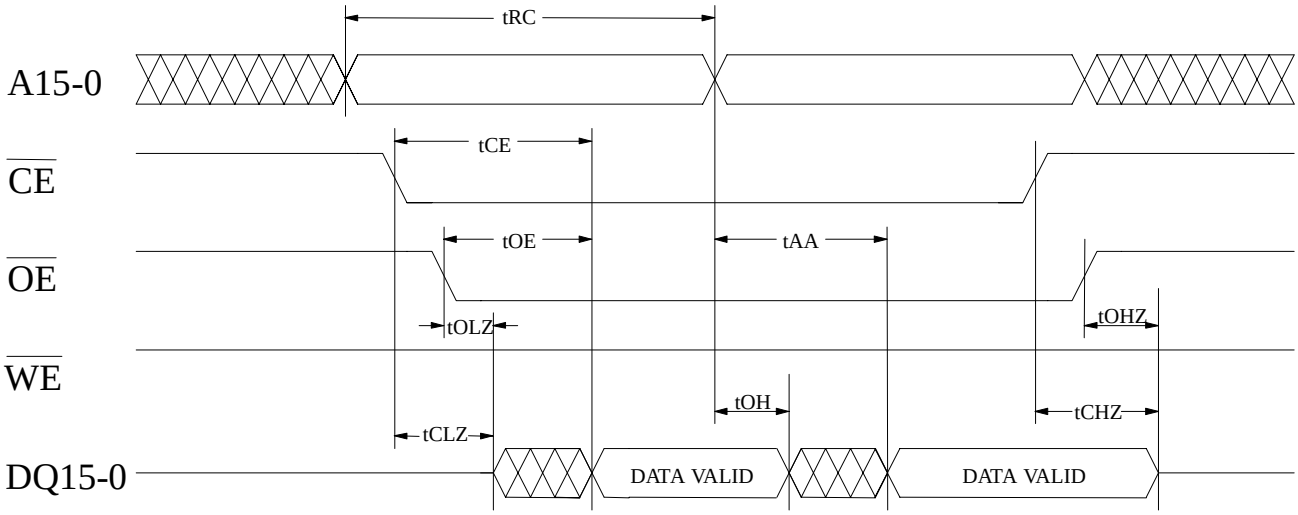


Figure 6: $\overline{WE}$ Controlled Write Cycle Timing Diagram

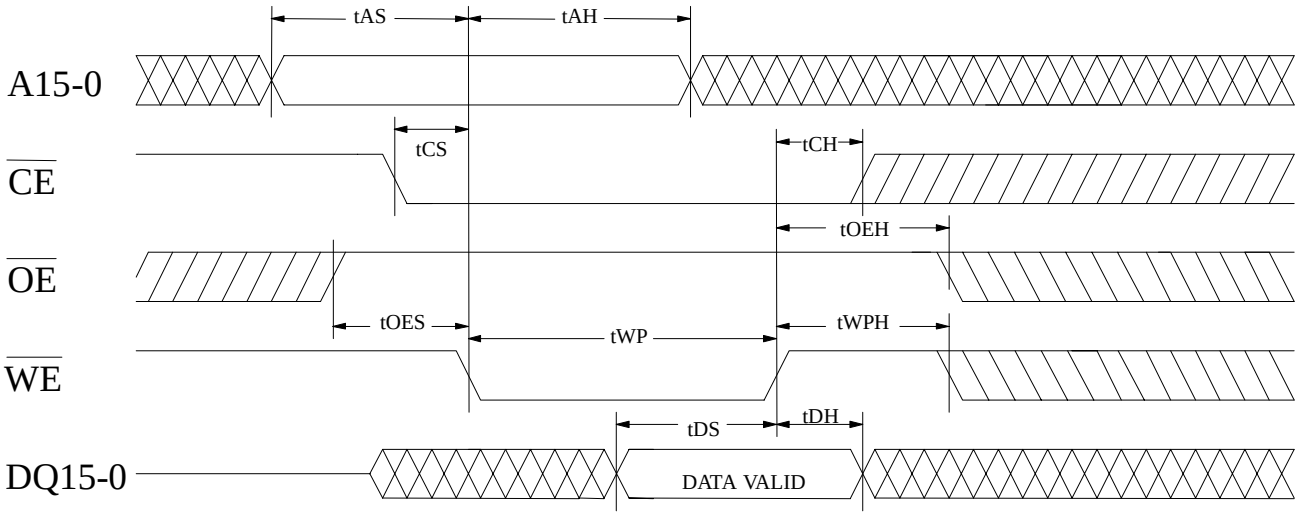


Figure 7: $\overline{CE}$ Controlled Write Cycle Timing Diagram

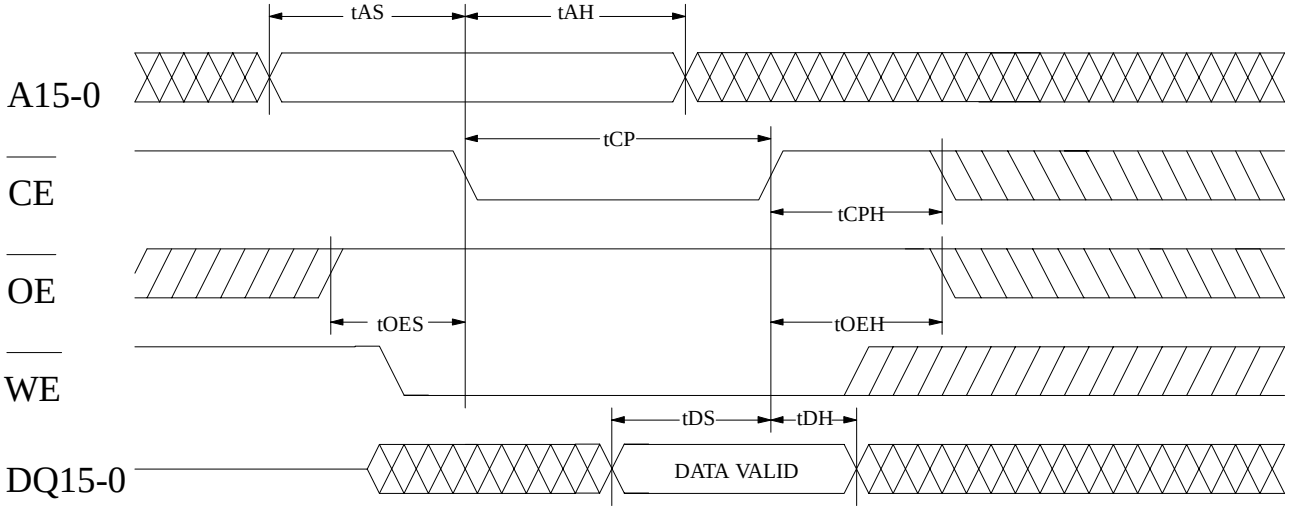


Figure 8: Sector Erase Timing Diagram

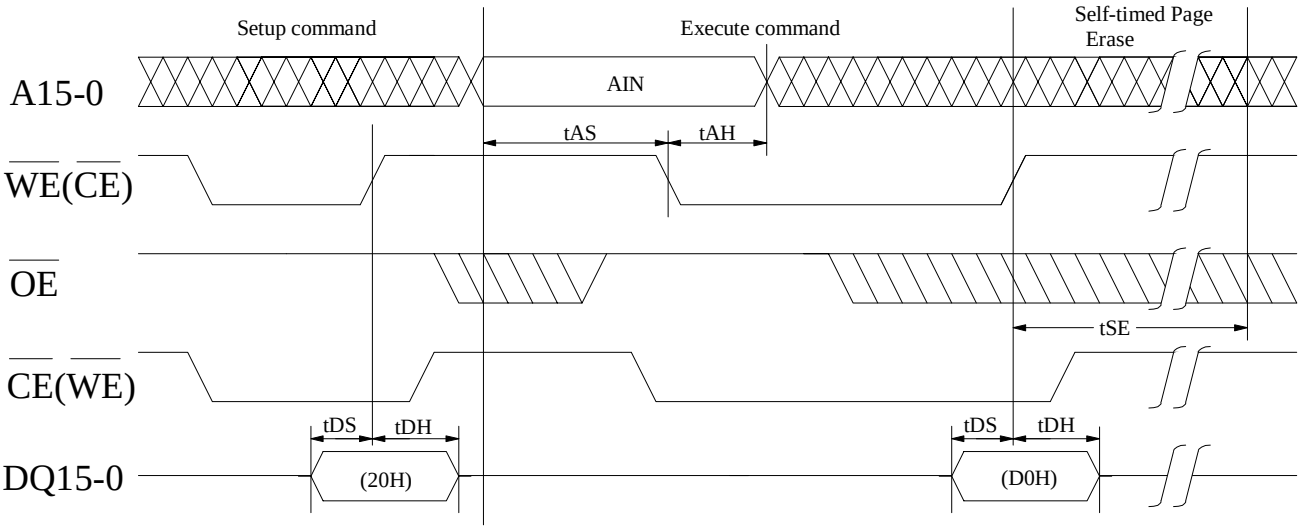


Figure 9: Word Program Timing Diagram

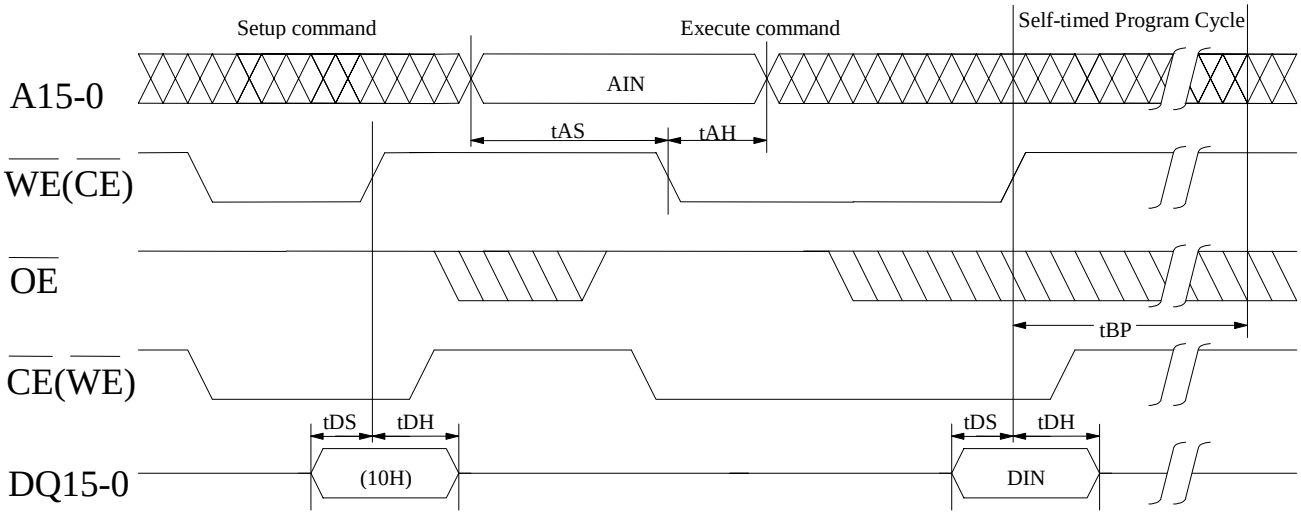


Figure 10: Reset Command Timing Diagram

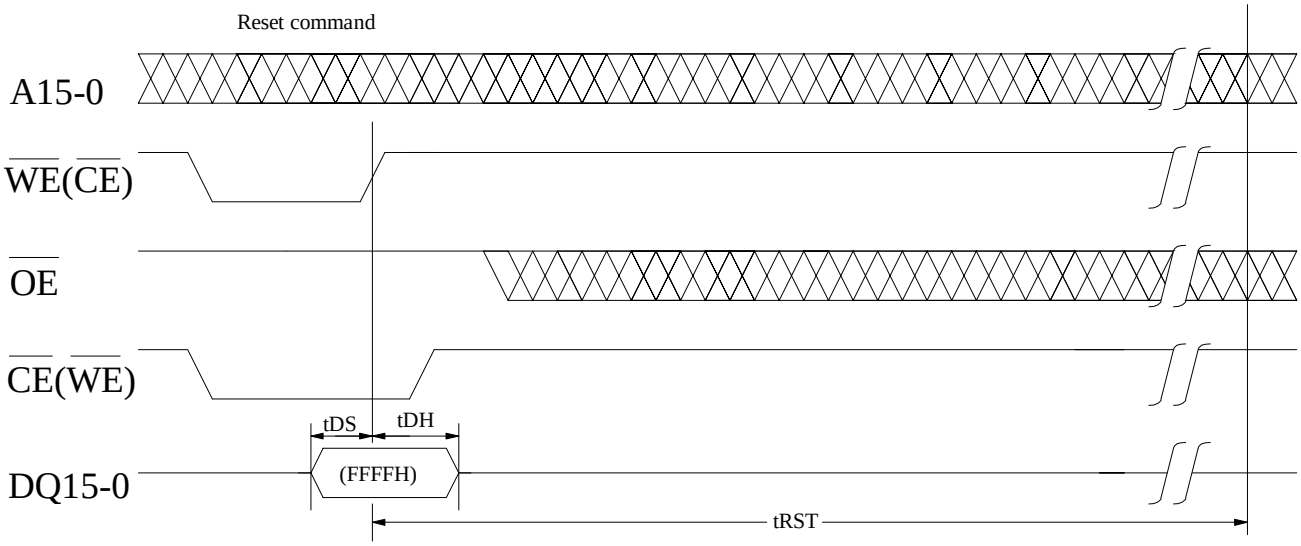
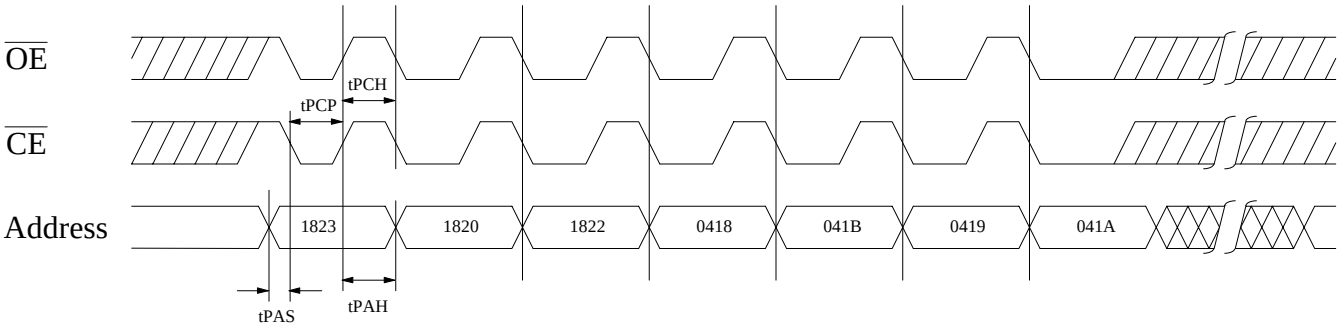


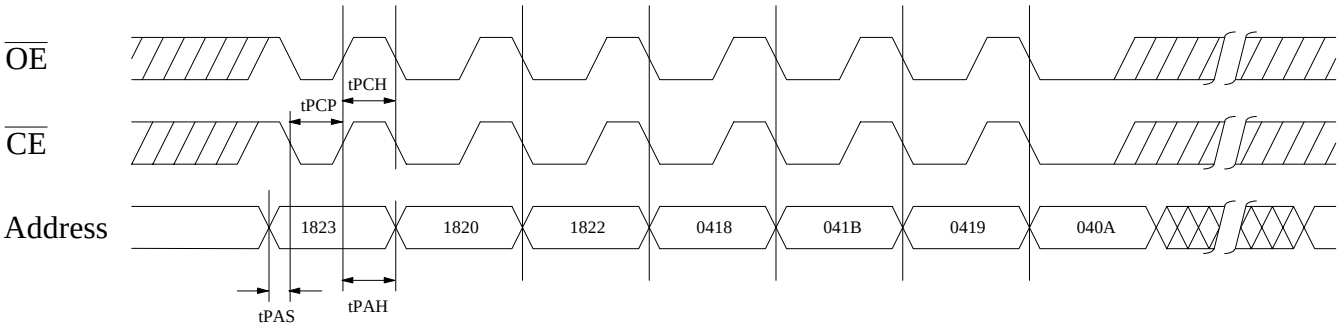
Figure 11: Software Data Unprotect Sequence



Notes on Figure 11

1. The address is latched on the rising edge of $\overline{CE}$ or $\overline{OE}$, whichever is earlier.

Figure 12: Software Data Protect Sequence



Notes on Figure 12

1. The address is latched on the rising edge of $\overline{CE}$ or $\overline{OE}$, whichever is earlier.

Figure 13: $\overline{\text{DATA}}$ Polling Timing Diagram (DQ7)

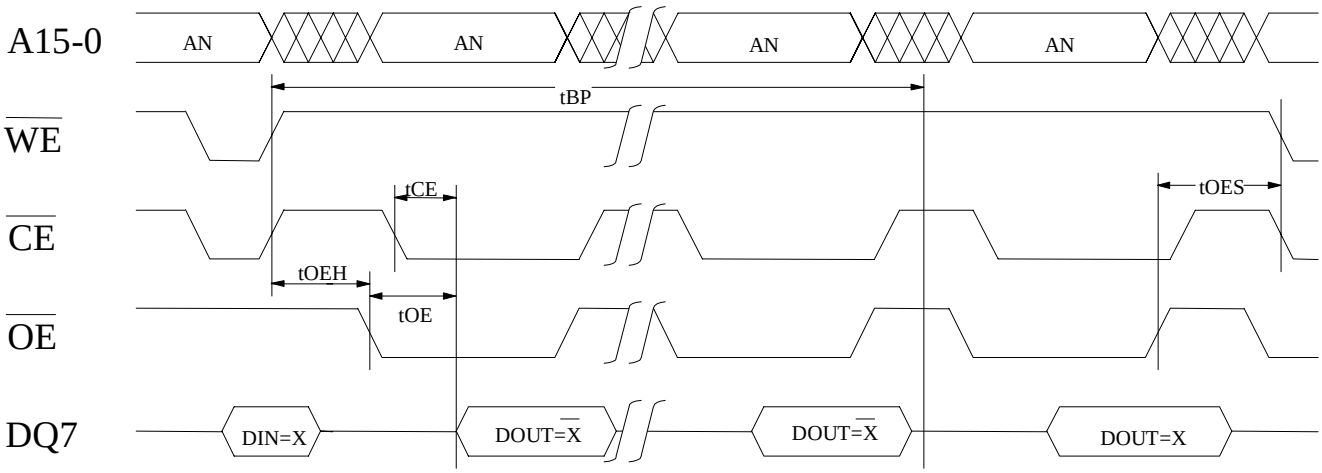
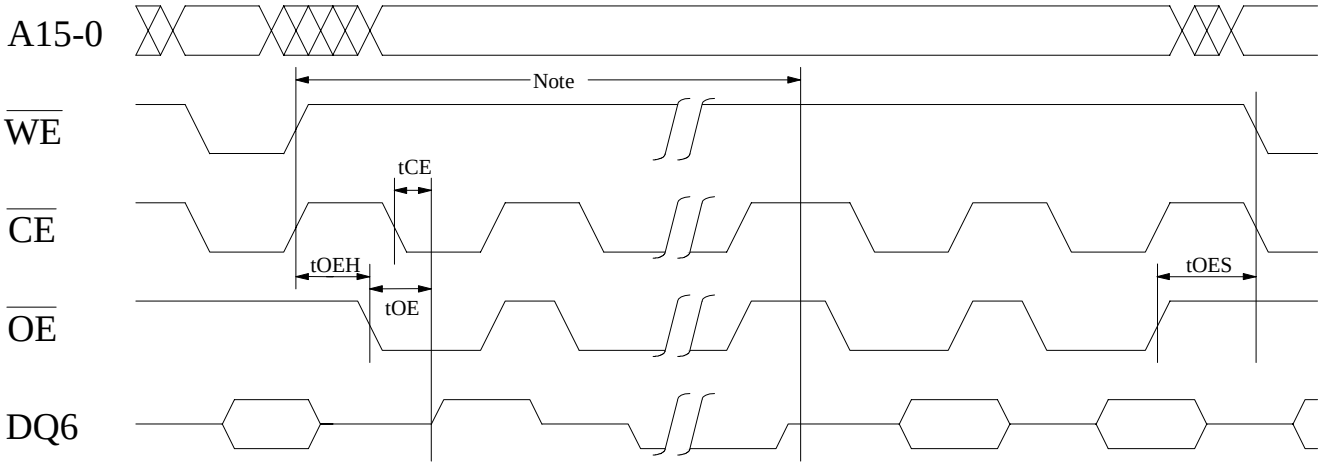


Figure 14: Toggle Bit Timing Diagram (DQ6)



Note: This time interval signal can be tSE or tBP, depending upon the selected operation mode.

1. Noproducts described or contained herein are intended for use in surgical implants, life-support systems aerospace equipment, nuclear power control systems, vehicles, disaster/crime-prevention equipment and the like, then failure of which may directly or indirectly cause injury, death or property loss.

2. Anyone purchasing any products described or contained herein for an above-mentioned use shall:
   a) Accept full responsibility and indemnify and defend SANYO ELECTRIC CO.,LTD., its affiliates, subsidiaries and distributors and all their officers and employees, jointly and severally, against any and all claims and litigation and all damages, cost and expenses associated with such use:

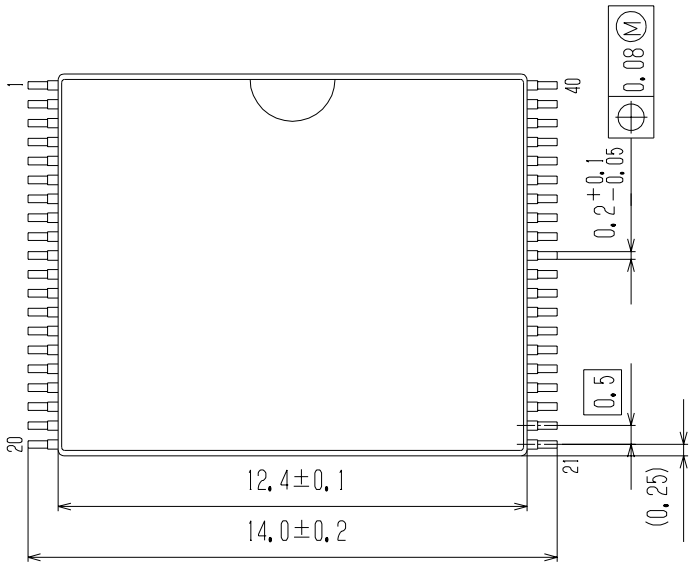
   b) Not impose any responsibility for any fault or negligence, which may be cited in any such claim or litigation on SANYO ELECTRIC CO., LTD., its affiliates, subsidiaries and distributor or any of their officers and employees jointly or sever ally.

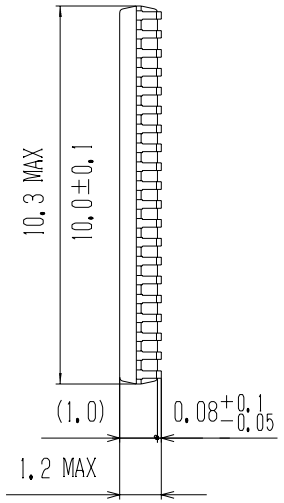
3.Information (including circuit diagrams and circuit parameter) herein in for example only; it is not guaranteed for volume production. SANYO believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringement of intellectual property rights or other rights of third parties.

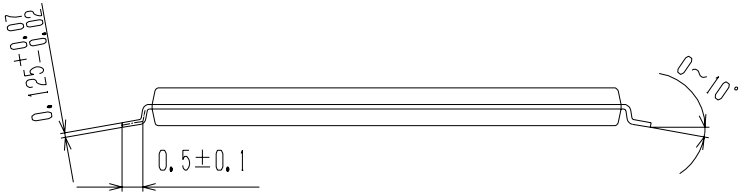
OUTLINE DRAWING

SANYO

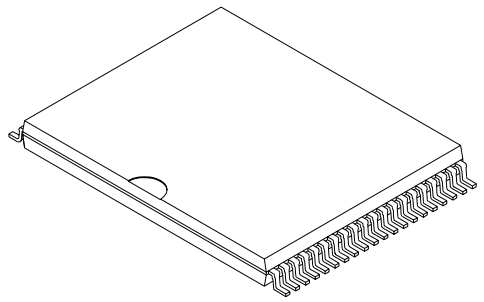
SANYO Package Code	EIAJ Package Code	JEDEC Package Code	TYPE NUMBER	ENACT No.	Weight(g)	Measure	Unit
TSOP40A(10*14)	———	———	———	S−044	0.3	5/1	mm







Appearance



TSOP40A(10*14)

REVISION : 3

SANYO : Thin Small Outline Package 40Pin Plastic